

**Notice of References Cited**

Application/Control No.

10/581,633

Applicant(s)/Patent Under  
Reexamination  
SHIMA ET AL.

Examiner

ANNA L. VERDERAME

Art Unit

1795

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,390,547	06-2008	Kim et al.	428/64.1
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.